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Details

Product Status	Active
Core Processor	ARM® Cortex®-M0
Core Size	32-Bit Single-Core
Speed	32MHz
Connectivity	I ² C, LINbus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, I ² S, POR, PWM, WDT
Number of I/O	11
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 5.5V
Data Converters	A/D 6x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	16-TSSOP (0.173", 4.40mm Width)
Supplier Device Package	PG-TSSOP-16-8
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/xmc1100t016x0064abxuma1

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Table of Contents

1	Summary of Features	7
1.1	Ordering Information	8
1.2	Device Types	9
1.3	Device Type Features	10
1.4	Chip Identification Number	10
2	General Device Information	13
2.1	Logic Symbols	13
2.2	Pin Configuration and Definition	15
2.2.1	Package Pin Summary	18
2.2.2	Port I/O Function Description	20
2.2.3	Hardware Controlled I/O Function Description	22
3	Electrical Parameter	27
3.1	General Parameters	27
3.1.1	Parameter Interpretation	27
3.1.2	Absolute Maximum Ratings	28
3.1.3	Pin Reliability in Overload	28
3.1.4	Operating Conditions	31
3.2	DC Parameters	32
3.2.1	Input/Output Characteristics	32
3.2.2	Analog to Digital Converters (ADC)	36
3.2.3	Temperature Sensor Characteristics	40
3.2.4	Power Supply Current	41
3.2.5	Flash Memory Parameters	46
3.3	AC Parameters	47
3.3.1	Testing Waveforms	47
3.3.2	Power-Up and Supply Monitoring Characteristics	48
3.3.3	On-Chip Oscillator Characteristics	50
3.3.4	Serial Wire Debug Port (SW-DP) Timing	52
3.3.5	SPD Timing Requirements	53
3.3.6	Peripheral Timings	54
3.3.6.1	Synchronous Serial Interface (USIC SSC) Timing	54
3.3.6.2	Inter-IC (IIC) Interface Timing	57
3.3.6.3	Inter-IC Sound (IIS) Interface Timing	59
4	Package and Reliability	61
4.1	Package Parameters	61
4.1.1	Thermal Considerations	61
4.2	Package Outlines	63
5	Quality Declaration	67

Summary of Features

- Q: VQFN
- <PPP> package pin count
- <T> the temperature range:
 - F: -40°C to 85°C
 - X: -40°C to 105°C
- <FFFF> the Flash memory size.

For ordering codes for the XMC1100 please contact your sales representative or local distributor.

This document describes several derivatives of the XMC1100 series, some descriptions may not apply to a specific product. Please see [Table 1](#).

For simplicity the term **XMC1100** is used for all derivatives throughout this document.

1.2 Device Types

These device types are available and can be ordered through Infineon's direct and/or distribution channels.

Table 1 Synopsis of XMC1100 Device Types

Derivative	Package	Flash Kbytes	SRAM Kbytes
XMC1100-T016F0008	PG-TSSOP-16-8	8	16
XMC1100-T016F0016	PG-TSSOP-16-8	16	16
XMC1100-T016F0032	PG-TSSOP-16-8	32	16
XMC1100-T016F0064	PG-TSSOP-16-8	64	16
XMC1100-T016X0016	PG-TSSOP-16-8	16	16
XMC1100-T016X0032	PG-TSSOP-16-8	32	16
XMC1100-T016X0064	PG-TSSOP-16-8	64	16
XMC1100-T038F0016	PG-TSSOP-38-9	16	16
XMC1100-T038F0032	PG-TSSOP-38-9	32	16
XMC1100-T038F0064	PG-TSSOP-38-9	64	16
XMC1100-T038X0064	PG-TSSOP-38-9	64	16
XMC1100-Q024F0008	PG-VQFN-24-19	8	16
XMC1100-Q024F0016	PG-VQFN-24-19	16	16
XMC1100-Q024F0032	PG-VQFN-24-19	32	16
XMC1100-Q024F0064	PG-VQFN-24-19	64	16
XMC1100-Q040F0016	PG-VQFN-40-13	16	16

Summary of Features

Table 4 XMC1100 Chip Identification Number (cont'd)

Derivative	Value	Marking
XMC1100-Q040F0032	00011042 01CF00FF 00001F37 00000000 00000C00 00001000 00009000 201ED083 _H	AB
XMC1100-Q040F0064	00011042 01CF00FF 00001F37 00000000 00000C00 00001000 00011000 201ED083 _H	AB

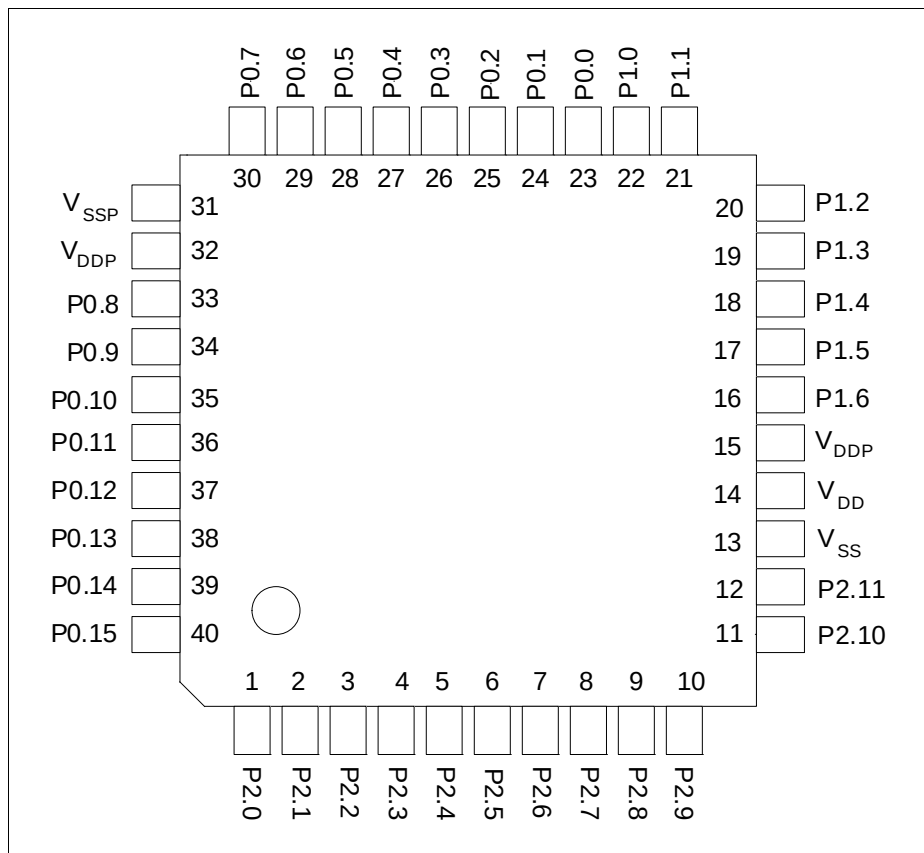


Figure 7 XMC1100 PG-VQFN-40 Pin Configuration (top view)

General Device Information
Table 6 Package Pin Mapping (cont'd)

Function	VQFN 40	TSSOP 38	VQFN 24	TSSOP 16	Pad Type	Notes
P0.13	38	32	22	-	STD_INOUT	
P0.14	39	33	23	13	STD_INOUT	
P0.15	40	34	24	14	STD_INOUT	
P1.0	22	16	14	-	High Current	
P1.1	21	15	13	-	High Current	
P1.2	20	14	12	-	High Current	
P1.3	19	13	11	-	High Current	
P1.4	18	12	-	-	High Current	
P1.5	17	11	-	-	High Current	
P1.6	16	-	-	-	STD_INOUT	
P2.0	1	35	1	15	STD_INOUT/ AN	
P2.1	2	36	2	-	STD_INOUT/ AN	
P2.2	3	37	3	-	STD_IN/AN	
P2.3	4	38	-	-	STD_IN/AN	
P2.4	5	1	-	-	STD_IN/AN	
P2.5	6	2	-	-	STD_IN/AN	
P2.6	7	3	4	16	STD_IN/AN	
P2.7	8	4	5	1	STD_IN/AN	
P2.8	9	5	5	1	STD_IN/AN	
P2.9	10	6	6	2	STD_IN/AN	
P2.10	11	7	7	3	STD_INOUT/ AN	
P2.11	12	8	8	4	STD_INOUT/ AN	
VSS	13	9	9	5	Power	Supply GND, ADC reference GND
VDD	14	10	10	6	Power	Supply VDD, ADC reference voltage/ ORC reference voltage

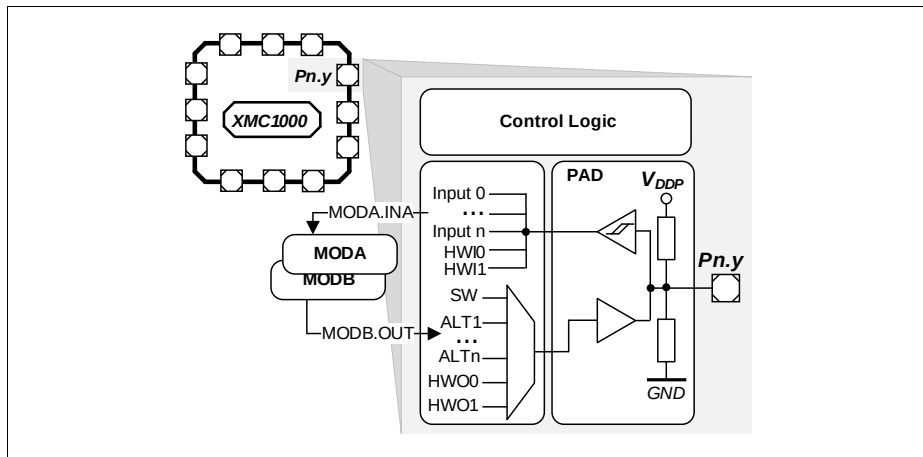


Figure 8 Simplified Port Structure

Pn.y is the port pin name, defining the control and data bits/registers associated with it. As GPIO, the port is under software control. Its input value is read via Pn_IN.y, Pn_OUT defines the output value.

Up to seven alternate output functions (ALT1/2/3/4/5/6/7) can be mapped to a single port pin, selected by Pn_IOC.R.PC. The output value is directly driven by the respective module, with the pin characteristics controlled by the port registers (within the limits of the connected pad).

The port pin input can be connected to multiple peripherals. Most peripherals have an input multiplexer to select between different possible input sources.

The input path is also active while the pin is configured as output. This allows to feedback an output to on-chip resources without wasting an additional external pin.

Please refer to the [Port I/O Functions](#) table for the complete Port I/O function mapping.

Table 9 Port I/O Functions

Function	Outputs							Inputs						
	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7	Input	Input	Input	Input	Input	Input	Input
P0.0	ERU0. PDOUT0		ERU0. GOUT0	CCU40.OUT 0		USIC0_CH0. SELO0	USIC0_CH1. SELO0	CCU40.IN0C				USIC0_CH0. DX2A	USIC0_CH1. DX2A	
P0.1	ERU0. PDOUT1		ERU0. GOUT1	CCU40.OUT 1			SCU. VDROP	CCU40.IN1C						
P0.2	ERU0. PDOUT2		ERU0. GOUT2	CCU40.OUT 2		VADC0. EMUX02		CCU40.IN2C						
P0.3	ERU0. PDOUT3		ERU0. GOUT3	CCU40.OUT 3		VADC0. EMUX01		CCU40.IN3C						
P0.4				CCU40.OUT 1		VADC0. EMUX00	WWDT. SERVICE_O UT							
P0.5				CCU40.OUT 0										
P0.6				CCU40.OUT 0		USIC0_CH1. MCLKOUT	USIC0_CH1. DOUT0	CCU40.IN0B				USIC0_CH1. DX0C		
P0.7				CCU40.OUT 1		USIC0_CH0. SCLKOUT	USIC0_CH1. DOUT0	CCU40.IN1B				USIC0_CH0. DX1C	USIC0_CH1. DX0D	USIC0_CH1. DX1C
P0.8				CCU40.OUT 2		USIC0_CH0. SCLKOUT	USIC0_CH1. SCLKOUT	CCU40.IN2B				USIC0_CH0. DX1B	USIC0_CH1. DX1B	
P0.9				CCU40.OUT 3		USIC0_CH0. SELO0	USIC0_CH1. SELO0	CCU40.IN3B				USIC0_CH0. DX2B	USIC0_CH1. DX2B	
P0.10						USIC0_CH0. SELO1	USIC0_CH1. SELO1					USIC0_CH0. DX2C	USIC0_CH1. DX2C	
P0.11				USIC0_CH0. MCLKOUT		USIC0_CH0. SELO2	USIC0_CH1. SELO2					USIC0_CH0. DX2D	USIC0_CH1. DX2D	
P0.12						USIC0_CH0. SELO3		CCU40.IN0A	CCU40.IN1A	CCU40.IN2A	CCU40.IN3A	USIC0_CH0. DX2E		
P0.13	WWDT. SERVICE_O UT					USIC0_CH0. SELO4						USIC0_CH0. DX2F		
P0.14						USIC0_CH0. DOUT0	USIC0_CH0. SCLKOUT					USIC0_CH0. DX0A	USIC0_CH0. DX1A	
P0.15						USIC0_CH0. DOUT0	USIC0_CH1. MCLKOUT					USIC0_CH0. DX0B		
P1.0		CCU40.OUT 0					USIC0_CH0. DOUT0					USIC0_CH0. DX0C		

Table 10 Hardware Controlled I/O Functions

Function	Outputs		Inputs		Pull Control			
	HWO0	HWO1	HWI0	HWI1	HW0_PD	HW0_PU	HW1_PD	HW1_PU
P0.0								
P0.1								
P0.2								
P0.3								
P0.4								
P0.5								
P0.6								
P0.7								
P0.8								
P0.9								
P0.10								
P0.11								
P0.12								
P0.13								
P0.14								
P0.15								
P1.0		USIC0_CH0. DOUT0		USIC0_CH0. HWIN0				
P1.1		USIC0_CH0. DOUT1		USIC0_CH0. HWIN1				
P1.2		USIC0_CH0. DOUT2		USIC0_CH0. HWIN2				
P1.3		USIC0_CH0. DOUT3		USIC0_CH0. HWIN3				
P1.4								
P1.5								
P1.6								
P2.0								
P2.1								
P2.2							CCU40.OUT3	CCU40.OUT3
P2.3								
P2.4								

3 Electrical Parameter

This section provides the electrical parameter which are implementation-specific for the XMC1100.

3.1 General Parameters

3.1.1 Parameter Interpretation

The parameters listed in this section represent partly the characteristics of the XMC1100 and partly its requirements on the system. To aid interpreting the parameters easily when evaluating them for a design, they are indicated by the abbreviations in the "Symbol" column:

- **CC**
Such parameters indicate **C**ontroller **C**haracteristics, which are distinctive feature of the XMC1100 and must be regarded for a system design.
- **SR**
Such parameters indicate **S**ystem **R**equirements, which must be provided by the application system in which the XMC1100 is designed in.

Electrical Parameter

If a pin current is outside of the **Operating Conditions** but within the overload conditions, then the parameters of this pin as stated in the Operating Conditions can no longer be guaranteed. Operation is still possible in most cases but with relaxed parameters.

Note: An overload condition on one or more pins does not require a reset.

Note: A series resistor at the pin to limit the current to the maximum permitted overload current is sufficient to handle failure situations like short to battery.

Table 12 Overload Parameters

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Input current on any port pin during overload condition	I_{OV} SR	-5	—	5	mA	
Absolute sum of all input circuit currents during overload condition	I_{OVS} SR	—	—	25	mA	

Figure 9 shows the path of the input currents during overload via the ESD protection structures. The diodes against V_{DDP} and ground are a simplified representation of these ESD protection structures.

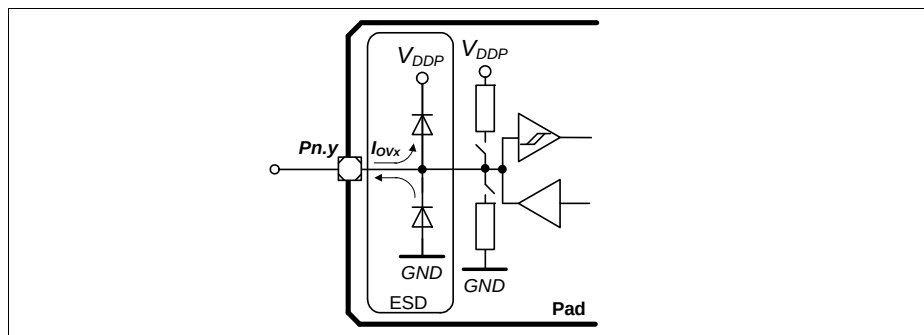


Figure 9 Input Overload Current via ESD structures

Table 13 and **Table 14** list input voltages that can be reached under overload conditions. Note that the absolute maximum input voltages as defined in the **Absolute Maximum Ratings** must not be exceeded during overload.

Electrical Parameter
Table 16 Input/Output Characteristics (Operating Conditions apply) (cont'd)

Parameter	Symbol		Limit Values		Unit	Test Conditions
			Min.	Max.		
Input low voltage on port pins (Large Hysteresis)	V_{ILPL}	SR	–	$0.08 \times V_{DDP}$	V	CMOS Mode (5 V, 3.3 V & 2.2 V) ¹⁰⁾
Input high voltage on port pins (Large Hysteresis)	V_{IHPL}	SR	$0.85 \times V_{DDP}$	–	V	CMOS Mode (5 V, 3.3 V & 2.2 V) ¹⁰⁾
Rise time on High Current Pad ¹⁾	t_{HCPR}	CC	–	9	ns	50 pF @ 5 V ²⁾
			–	12	ns	50 pF @ 3.3 V ³⁾
			–	25	ns	50 pF @ 1.8 V ⁴⁾
Fall time on High Current Pad ¹⁾	t_{HCPF}	CC	–	9	ns	50 pF @ 5 V ²⁾
			–	12	ns	50 pF @ 3.3 V ³⁾
			–	25	ns	50 pF @ 1.8 V ⁴⁾
Rise time on Standard Pad ¹⁾	t_R	CC	–	12	ns	50 pF @ 5 V ⁵⁾
			–	15	ns	50 pF @ 3.3 V ⁶⁾
			–	31	ns	50 pF @ 1.8 V ⁷⁾
Fall time on Standard Pad ¹⁾	t_F	CC	–	12	ns	50 pF @ 5 V ⁵⁾
			–	15	ns	50 pF @ 3.3 V ⁶⁾
			–	31	ns	50 pF @ 1.8 V ⁷⁾
Input Hysteresis ⁸⁾	HYS	CC	$0.08 \times V_{DDP}$	–	V	CMOS Mode (5 V), Standard Hysteresis
			$0.03 \times V_{DDP}$	–	V	CMOS Mode (3.3 V), Standard Hysteresis
			$0.02 \times V_{DDP}$	–	V	CMOS Mode (2.2 V), Standard Hysteresis
			$0.5 \times V_{DDP}$	$0.75 \times V_{DDP}$	V	CMOS Mode(5 V), Large Hysteresis
			$0.4 \times V_{DDP}$	$0.75 \times V_{DDP}$	V	CMOS Mode(3.3 V), Large Hysteresis
			$0.2 \times V_{DDP}$	$0.65 \times V_{DDP}$	V	CMOS Mode(2.2 V), Large Hysteresis

Electrical Parameter
Table 17 ADC Characteristics (Operating Conditions apply)¹⁾ (cont'd)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Gain settings	G_{IN} CC	1			–	GNCTRxz.GAINy = 00 _B (unity gain)
		3			–	GNCTRxz.GAINy = 01 _B (gain g1)
		6			–	GNCTRxz.GAINy = 10 _B (gain g2)
		12			–	GNCTRxz.GAINy = 11 _B (gain g3)
Sample Time	t_{sample} CC	4	–	–	1 / f_{ADC}	$V_{DD} = 5.0$ V
		4	–	–	1 / f_{ADC}	$V_{DD} = 3.3$ V
		30	–	–	1 / f_{ADC}	$V_{DD} = 2.0$ V
Sigma delta loop hold time	t_{SD_hold} CC	20	–	–	μs	Residual charge stored in an active sigma delta loop remains available
Conversion time in fast compare mode	t_{CF} CC	9			1 / f_{ADC}	²⁾
Conversion time in 12-bit mode	t_{C12} CC	20			1 / f_{ADC}	²⁾
Maximum sample rate in 12-bit mode ³⁾	f_{C12} CC	–	–	$f_{ADC} / 43.5$	–	1 sample pending
		–	–	$f_{ADC} / 63.5$	–	2 samples pending
Conversion time in 10-bit mode	t_{C10} CC	18			1 / f_{ADC}	²⁾
Maximum sample rate in 10-bit mode ³⁾	f_{C10} CC	–	–	$f_{ADC} / 41.5$	–	1 sample pending
		–	–	$f_{ADC} / 59.5$	–	2 samples pending
Conversion time in 8-bit mode	t_{C8} CC	16			1 / f_{ADC}	²⁾

Electrical Parameter

Table 17 ADC Characteristics (Operating Conditions apply)¹⁾ (cont'd)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Maximum sample rate in 8-bit mode ³⁾	f_{C8} CC	–	–	$f_{ADC} / 38.5$	–	1 sample pending
		–	–	$f_{ADC} / 54.5$	–	2 samples pending
RMS noise ⁴⁾	EN_{RMS} CC	–	1.5	–	LSB 12	DC input, $V_{DD} = 5.0$ V, $V_{AIN} = 2.5$ V, 25°C
DNL error	EA_{DNL} CC	–	±2.0	–	LSB 12	
INL error	EA_{INL} CC	–	±4.0	–	LSB 12	
Gain error with external reference	EA_{GAIN} CC	–	±0.5	–	%	SHSCFG.AREF = 00 _B (calibrated)
Gain error with internal reference ⁵⁾	EA_{GAIN} CC	–	±3.6	–	%	SHSCFG.AREF = 1X _B (calibrated), -40°C - 105°C
		–	±2.0	–	%	SHSCFG.AREF = 1X _B (calibrated), 0°C - 85°C
Offset error	EA_{OFF} CC	–	±8.0	–	mV	Calibrated, $V_{DD} = 5.0$ V

1) The parameters are defined for ADC clock frequency $f_{SH} = 32$ MHz.

2) No pending samples assumed, excluding sampling time and calibration.

3) Includes synchronization and calibration (average of gain and offset calibration).

4) This parameter can also be defined as an SNR value: $SNR[dB] = 20 \times \log(A_{MAXeff} / N_{RMS})$.

With $A_{MAXeff} = 2^N / 2$, $SNR[dB] = 20 \times \log(2048 / N_{RMS})$ [N = 12].

$N_{RMS} = 1.5$ LSB12, therefore, equals $SNR = 20 \times \log(2048 / 1.5) = 62.7$ dB.

5) Includes error from the reference voltage.

Table 19 Power Supply Parameters; $V_{DDP} = 5V$

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min	Typ. ¹⁾	Max.		
Sleep mode current Peripherals clock disabled Flash active f_{MCLK} / f_{PCLK} in MHz ⁵⁾	I_{DDPSD} CC	–	1.8	–	mA	32 / 64
			1.7	–	mA	24 / 48
			1.6	–	mA	16 / 32
			1.5	–	mA	8 / 16
			1.4	–	mA	1 / 1
Sleep mode current Peripherals clock disabled Flash powered down f_{MCLK} / f_{PCLK} in MHz ⁶⁾	I_{DDPSR} CC	–	1.2	–	mA	32 / 64
			1.1	–	mA	24 / 48
			1.0	–	mA	16 / 32
			0.8	–	mA	8 / 16
			0.7	–	mA	1 / 1
Deep Sleep mode current ⁷⁾	I_{DDPDS} CC	–	0.24	–	mA	
Wake-up time from Sleep to Active mode ⁸⁾	t_{SSA} CC	–	6	–	cycles	
Wake-up time from Deep Sleep to Active mode ⁹⁾	t_{DSA} CC	–	280	–	μsec	

1) The typical values are measured at $T_A = +25\text{ °C}$ and $V_{DDP} = 5V$.

2) CPU and all peripherals clock enabled, Flash is in active mode.

3) CPU enabled, all peripherals clock disabled, Flash is in active mode.

4) CPU in sleep, all peripherals clock enabled and Flash is in active mode.

5) CPU in sleep, Flash is in active mode.

6) CPU in sleep, Flash is powered down and code executed from RAM after wake-up.

7) CPU in sleep, peripherals clock disabled, Flash is powered down and code executed from RAM after wake-up.

8) CPU in sleep, Flash is in active mode during sleep mode.

9) CPU in sleep, Flash is in powered down mode during deep sleep mode.

Electrical Parameter

Table 20 provides the active current consumption of some modules operating at 5 V power supply at 25 °C. The typical values shown are used as a reference guide on the current consumption when these modules are enabled.

Table 20 Typical Active Current Consumption

Active Current Consumption	Symbol	Limit Values	Unit	Test Condition
		Typ.		
Baseload current	I_{CPUDDC}	5.04	mA	Modules including Core, SCU, PORT, memories, ANATOP ¹⁾
VADC and SHS	I_{ADCDDC}	3.4	mA	Set CGATCLR0.VADC to 1 ²⁾
USIC0	$I_{USIC0DDC}$	0.87	mA	Set CGATCLR0.USIC0 to 1 ³⁾
CCU40	$I_{CCU40DDC}$	0.94	mA	Set CGATCLR0.CCU40 to 1 ⁴⁾
WDT	I_{WDTDDC}	0.03	mA	Set CGATCLR0.WDT to 1 ⁵⁾
RTC	I_{RTCDDC}	0.01	mA	Set CGATCLR0.RTC to 1 ⁶⁾

1) Baseload current is measured with device running in user mode, MCLK=PCLK=32 MHz, with an endless loop in the flash memory. The clock to the modules stated in CGATSTAT0 are gated.

2) Active current is measured with: module enabled, MCLK=32 MHz, running in auto-scan conversion mode

3) Active current is measured with: module enabled, alternating messages sent to PC at 57.6kbaud every 200ms

4) Active current is measured with: module enabled, MCLK=PCLK=32 MHz, 1 CCU4 slice for PWM switching from 1500Hz and 1000Hz at regular intervals, 1 CCU4 slice in capture mode for reading period and duty cycle

5) Active current is measured with: module enabled, MCLK=32 MHz, time-out mode; WLB = 0, WUB = 0x00008000; WDT serviced every 1s

6) Active current is measured with: module enabled, MCLK=32 MHz, Periodic interrupt enabled

3.3 AC Parameters

3.3.1 Testing Waveforms

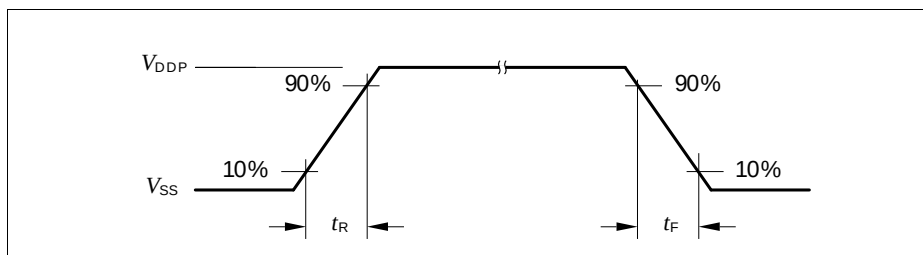


Figure 13 Rise/Fall Time Parameters

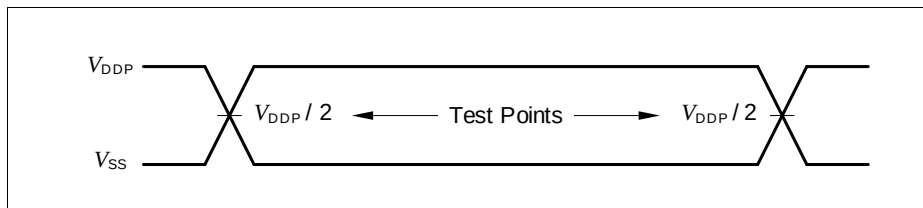


Figure 14 Testing Waveform, Output Delay

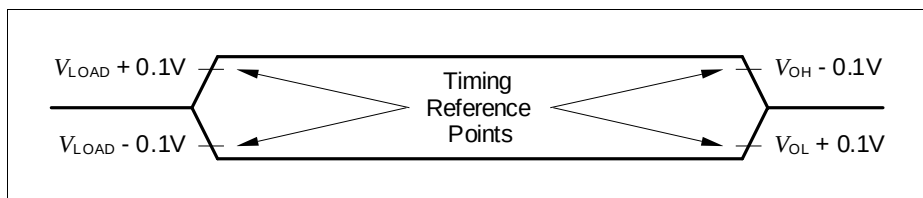


Figure 15 Testing Waveform, Output High Impedance

3.3.2 Power-Up and Supply Monitoring Characteristics

Table 22 provides the characteristics of the supply monitoring in XMC1100.

The guard band between the lowest valid operating voltage and the brownout reset threshold provides a margin for noise immunity and hysteresis. The electrical parameters may be violated while V_{DDP} is outside its operating range.

The brownout detection triggers a reset within the defined range. The prewarning detection can be used to trigger an early warning and issue corrective and/or fail-safe actions in case of a critical supply voltage drop.

Note: These parameters are not subject to production test, but verified by design and/or characterization.

Table 22 Power-Up and Supply Monitoring Parameters (Operating Conditions apply)¹⁾

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
V_{DDP} ramp-up time	t_{RAMPUP} SR	$V_{DDP}/S_{VDDPrise}$	–	10^7	μs	
V_{DDP} slew rate	S_{VDDPOP} SR	0	–	0.1	V/ μs	Slope during normal operation
	S_{VDDP10} SR	0	–	10	V/ μs	Slope during fast transient within +/- 10% of V_{DDP}
	$S_{VDDPrise}$ SR	0	–	10	V/ μs	Slope during power-on or restart after brownout event
	$S_{VDDPfall}$ ²⁾ SR	0	–	0.25	V/ μs	Slope during supply falling out of the +/- 10% limits ³⁾
V_{DDP} prewarning voltage	V_{DDPPW} CC	2.1	2.25	2.4	V	ANAVDEL.VDEL_SELECT = 00 _B
		2.85	3	3.15	V	ANAVDEL.VDEL_SELECT = 01 _B
		4.2	4.4	4.6	V	ANAVDEL.VDEL_SELECT = 10 _B

3.3.6.2 Inter-IC (IIC) Interface Timing

The following parameters are applicable for a USIC channel operated in IIC mode.

Note: Operating Conditions apply.

Table 29 USIC IIC Standard Mode Timing¹⁾

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Fall time of both SDA and SCL	t_1 CC/SR	-	-	300	ns	
Rise time of both SDA and SCL	t_2 CC/SR	-	-	1000	ns	
Data hold time	t_3 CC/SR	0	-	-	μs	
Data set-up time	t_4 CC/SR	250	-	-	ns	
LOW period of SCL clock	t_5 CC/SR	4.7	-	-	μs	
HIGH period of SCL clock	t_6 CC/SR	4.0	-	-	μs	
Hold time for (repeated) START condition	t_7 CC/SR	4.0	-	-	μs	
Set-up time for repeated START condition	t_8 CC/SR	4.7	-	-	μs	
Set-up time for STOP condition	t_9 CC/SR	4.0	-	-	μs	
Bus free time between a STOP and START condition	t_{10} CC/SR	4.7	-	-	μs	
Capacitive load for each bus line	C_b SR	-	-	400	pF	

1) Due to the wired-AND configuration of an IIC bus system, the port drivers of the SCL and SDA signal lines need to operate in open-drain mode. The high level on these lines must be held by an external pull-up device, approximately 10 kOhm for operation at 100 kbit/s, approximately 2 kOhm for operation at 400 kbit/s.

5 Quality Declaration

Table 34 shows the characteristics of the quality parameters in the XMC1100.

Table 34 Quality Parameters

Parameter	Symbol	Limit Values		Unit	Notes
		Min.	Max.		
ESD susceptibility according to Human Body Model (HBM)	V_{HBM} SR	-	2000	V	Conforming to EIA/JESD22-A114-B
ESD susceptibility according to Charged Device Model (CDM) pins	V_{CDM} SR	-	500	V	Conforming to JESD22-C101-C
Moisture sensitivity level	MSL CC	-	3	-	JEDEC J-STD-020D
Soldering temperature	T_{SDR} SR	-	260	°C	Profile according to JEDEC J-STD-020D